

TOSHIBA Transistor Silicon NPN Epitaxial Type (PCT Process) Silicon PNP Epitaxial Type (PCT Process)

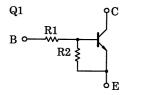
# **RN4988**

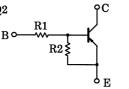
#### Switching, Inverter Circuit, Interface Circuit And Driver Circuit Applications

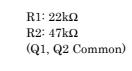
- Includeing two devices in US6 (ultra super mini type with 6 leads)
- With built-in bias resistors •
- Simplify circuit design •
- Reduce a quantity of parts and manufacturing process •

#### **Equivalent Circuit and Bias Resister Values**

Q2

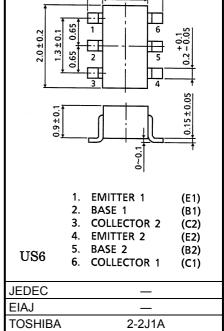






#### Q1 Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Collector-base voltage	V <sub>CBO</sub>	50	V
Collector-emitter voltage	V <sub>CEO</sub>	50	V
Emitter-base voltage	V <sub>EBO</sub>	7	V
Collector current	Ι <sub>C</sub>	100	mA



2.1 ± 0.1 1.25 ± 0.1

Weight: 6.8mg

#### Q2 Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Collector-base voltage	V <sub>CBO</sub>	-50	V
Collector-emitter voltage	V <sub>CEO</sub>	-50	V
Emitter-base voltage	V <sub>EBO</sub>	-7	V
Collector current	Ι <sub>C</sub>	-100	mA

## Q1, Q2 Common Maximum Ratings (Ta = 25°C)

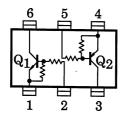
Characteristic	Symbol	Rating	Unit
Collector power dissipation	P <sub>C</sub> *	200	mW
Junction temperature	Tj	150	°C
Storage temperature range	T <sub>stg</sub>	-55~150	°C

\* : Total rating

### Marking



## Equivalent Circuit (Top View)



## Q1 Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I <sub>CBO</sub>	_	$V_{CB} = 50V, I_E = 0$	—	_	100	nA
	I <sub>CEO</sub>	_	V <sub>CE</sub> = 50V, I <sub>B</sub> = 0	—		500	
Emitter cut-off current	I <sub>EBO</sub>		V <sub>EB</sub> = 7V, I <sub>C</sub> = 0	0.078	-	0.145	mA
DC current gain	h <sub>FE</sub>	_	V <sub>CE</sub> = 5V, I <sub>C</sub> = 10mA	80	_	_	_
Collector-emitter saturation voltage	V <sub>CE (sat)</sub>	_	I <sub>C</sub> = 5mA, I <sub>B</sub> = 0.25mA	_	0.1	0.3	V
Input voltage (ON)	V <sub>I (ON)</sub>	_	V <sub>CE</sub> = 0.2V, I <sub>C</sub> = 5mA	1.0	_	2.6	V
Input voltage (OFF)	V <sub>I (OFF)</sub>		V <sub>CE</sub> = 5V, I <sub>C</sub> = 0.1mA	0.6	_	1.16	V
Transition frequency	f <sub>T</sub>	—	V <sub>CE</sub> = 10V, I <sub>C</sub> = 5mA	—	250	_	MHz
Collector output capacitance	C <sub>ob</sub>	_	V <sub>CB</sub> = 10V, I <sub>E</sub> = 0, f = 1 MHz	—	3	6	pF

#### Q2 Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Circui t	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I <sub>CBO</sub>	_	$V_{CB} = -50V, I_E = 0$	_	_	-100	nA
Collector cut-on current	ICEO	—	$V_{CE} = -50V, I_B = 0$	_	—	-500	
Emitter cut-off current	I <sub>EBO</sub>	—	V <sub>EB</sub> = -7V, I <sub>C</sub> = 0	-0.078	—	-0.145	mA
DC current gain	h <sub>FE</sub>	—	V <sub>CE</sub> = −5V, I <sub>C</sub> = −10mA	80	—	—	
Collector-emitter saturation voltage	V <sub>CE (sat)</sub>	—	I <sub>C</sub> = −5mA, I <sub>B</sub> = −0.25mA	_	-0.1	-0.3	V
Input voltage (ON)	V <sub>I (ON)</sub>	—	$V_{CE} = -0.2V, I_{C} = -5mA$	-1.0	—	-2.6	V
Input voltage (OFF)	VI (OFF)	—	V <sub>CE</sub> = −5V, I <sub>C</sub> = −0.1mA	-0.6	—	-1.16	V
Transition frequency	f <sub>T</sub>	—	V <sub>CE</sub> = −10V, I <sub>C</sub> = −5mA	_	200	—	MHz
Collector output capacitance	C <sub>ob</sub>	_	V <sub>CB</sub> = -10V, I <sub>E</sub> = 0	_	3	6	pF

## Q1, Q2 Common Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input resistor	R1	_	—	15.4	22	28.6	kΩ
Resistor ratio	R1/R2	—	_	0.421	0.468	0.515	—

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0.2

0.4

0.6

0.8

INPUT VOLTAGE VI(OFF) (V)

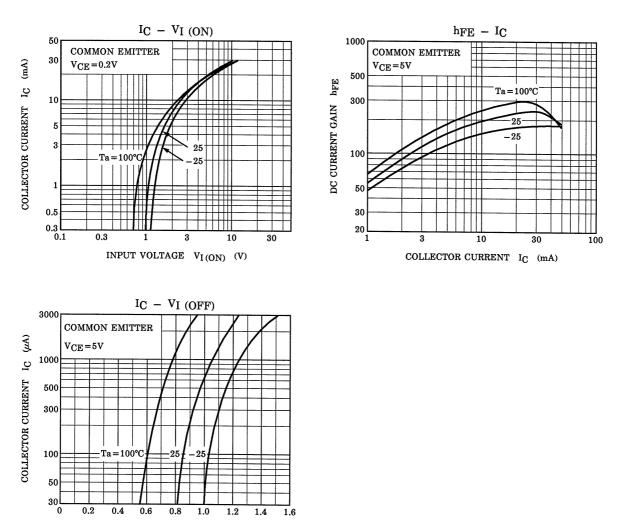
1.0

1.2

1.4

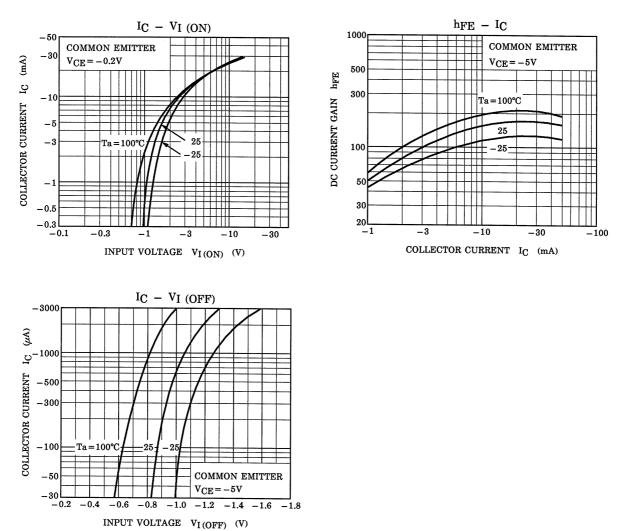
1.6

Q1



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Q2



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